

10/524778
DT1A PCT/PTO 16 FEB 2005

INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. ABE-026	Serial No. Not assigned
	Applicant: Shigeru UMENO et al.	
	Filing Date: February 16, 2005	Group: Not assigned

U.S. PATENT DOCUMENTS

Examiner's Initial		Document No.	Date	Name	Class	Sub Class	Filing Date If appropriate
	UA						
	UB						
	UC						
	UD						

FOREIGN PATENT DOCUMENTS

Examiner's Initial		Document No.	Date	Country	Translation Yes/No/Partial
Smm	FA	93/10557 A1	05/27/93	WO	Abstract
Smm	FB	0 969 505 A2	01/05/00	EP	
Smm	FC	2000-49063 A	02/18/00	JP	Translation
Smm	FD	7-66149	03/10/95	JP	Translation
Smm	FE	2001-274166 A	10/05/01	JP	Translation
Smm	FF	6-21033 A	01/28/94	JP	Translation
Smm	FG	2003-297840 A	10/17/03	JP	Translation
Smm	FH	9-22993 A	01/21/97	JP	Translation
Smm	FI	3085184 B2	07/07/00	JP	Translation
Smm	FJ	8-330316 A	12/13/96	JP	Translation

OTHER DOCUMENTS

Examiner's Initial		
Smm	DA	Umeno, Shigeru et al., "Dependence of Grown-in Defect Behavior on Oxygen Concentration in Czochralski Silicon Crystals", <i>Jpn. J. Appl. Phys.</i> , Vol. 38 (1999), pp. 5725-5730.
Smm	DB	Japan Institute of Invention and Innovation Journal of Technical Disclosure No. 98-477, February 2, 1998.
	DC	

Examiner:	Date Considered:
------------------	-------------------------

KTK/jbf